



Study on the readout of the ultra-low material RPC for background suppression in the MEG II experiment

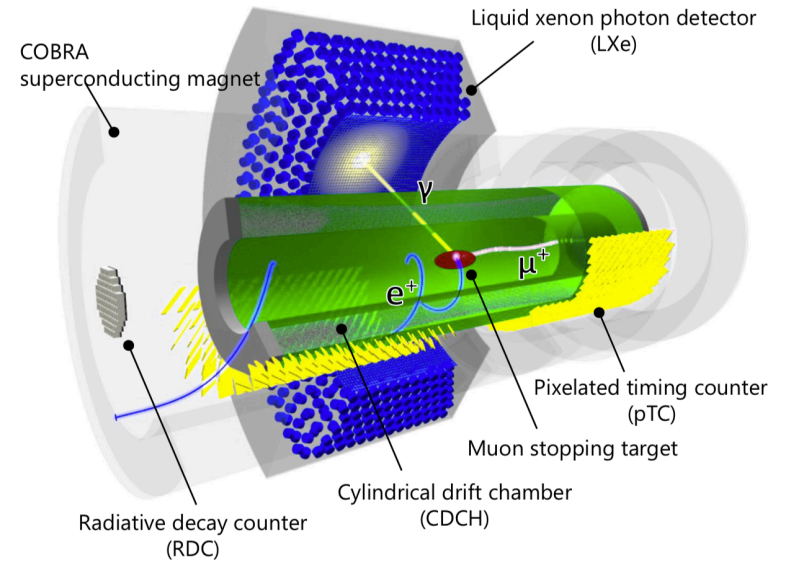
Kensuke Yamamoto

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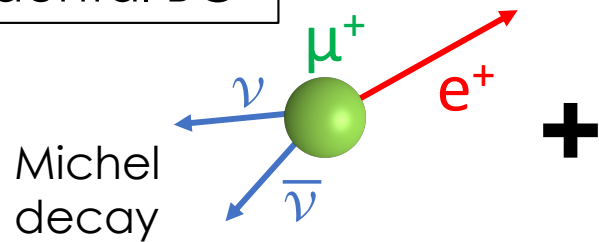
26th ICEPP Symposium on 16th February, 2020

MEG II & RPC

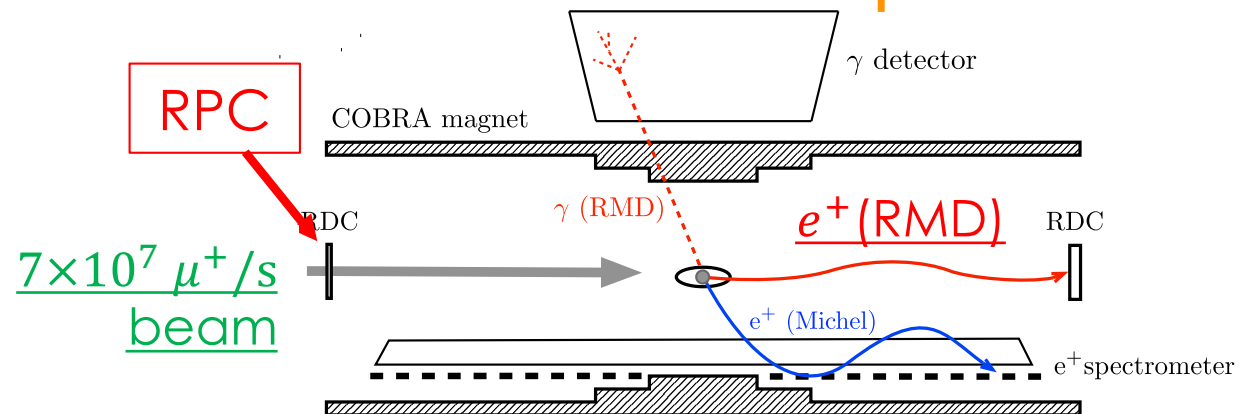
- MEG II searches for charged lepton flavour violating decay: $\mu^+ \rightarrow e^+ \gamma$



Accidental BG



- Resistive Plate Chamber (RPC) is one of gaseous detectors, uses high resistive electrodes placed face to face



Outline

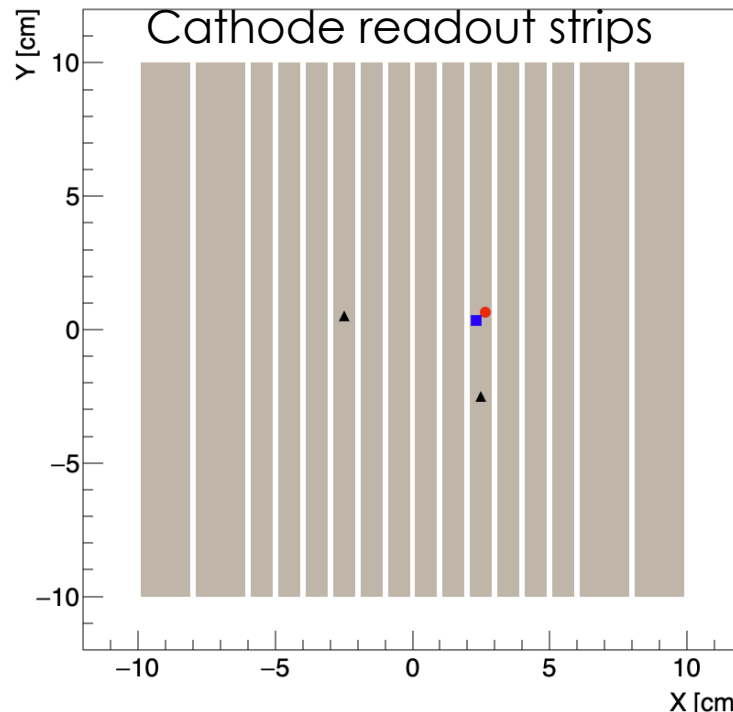
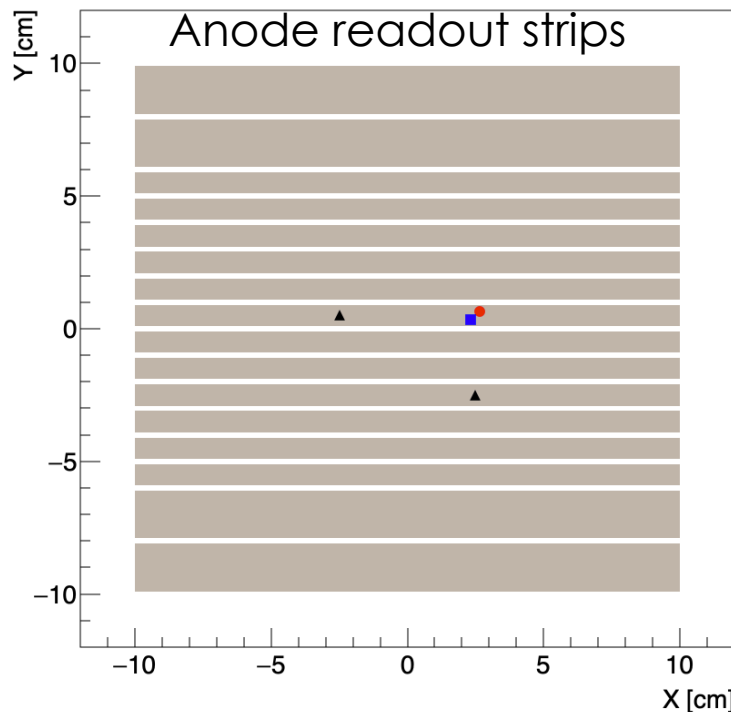
- Introduction of RPC readout
 - Pileup probability
 - Prototype RPC readout
 - Impedance matching
- Lab test
- Summary & prospects

Pileup study

Requirements for RPC

- 90% efficiency for 1-5 MeV e^+
- Rate capability
($10^8 \mu/s$ with 21 MeV/c)

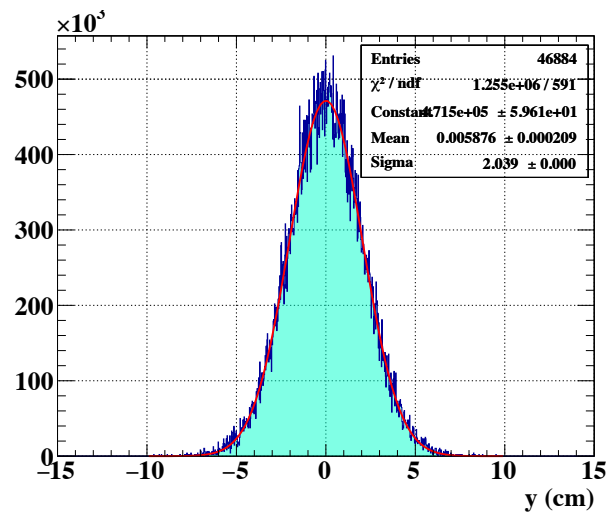
- Pileup of high-rate μ^+ beam & RMD e^+
 - Inefficiency of RMD e^+
 - Readout strips should be segmented



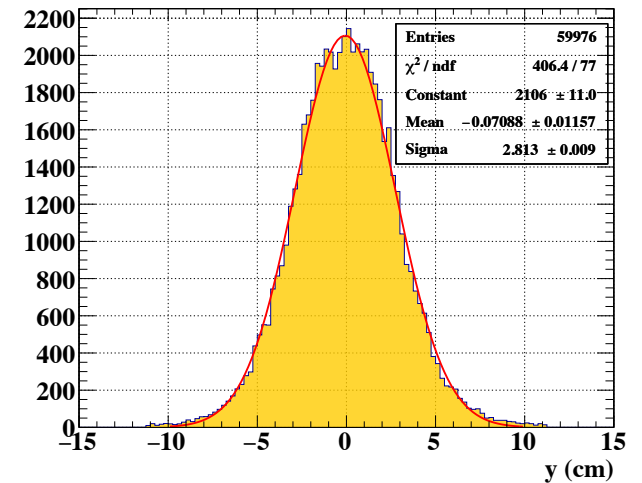
- : RMD e^+
- : μ^+ at the same position as RMD e^+
- ▲ : μ^+ in the same strip as RMD e^+

Pileup

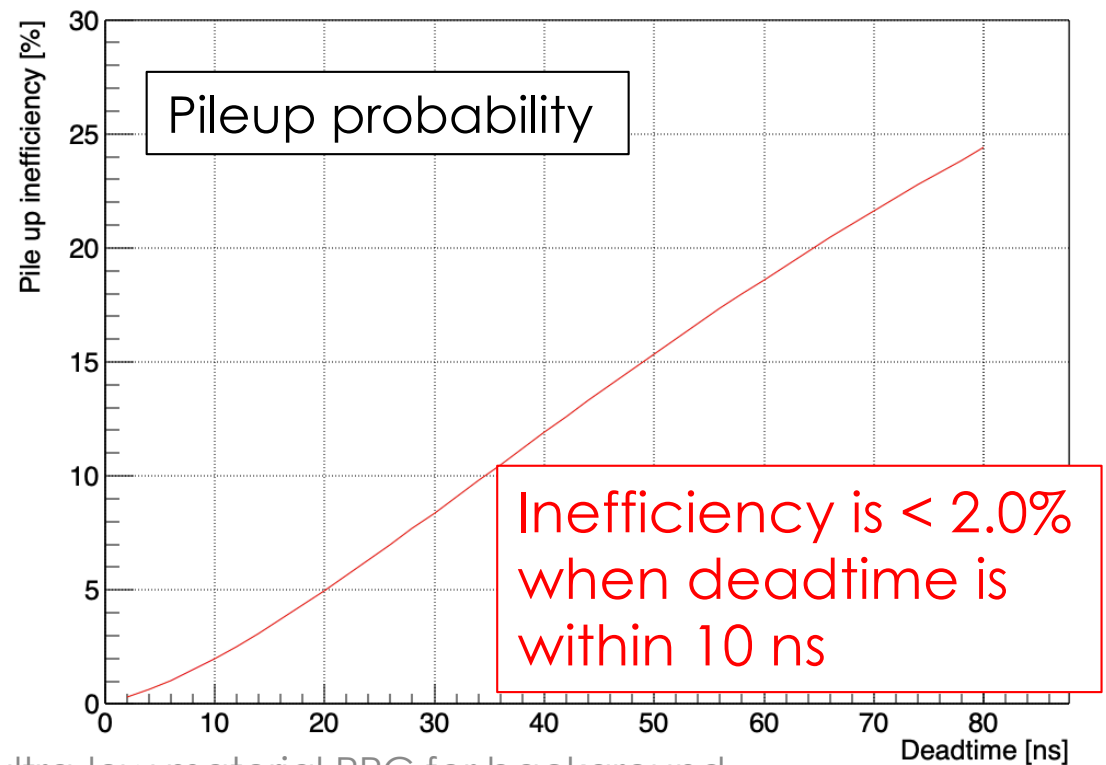
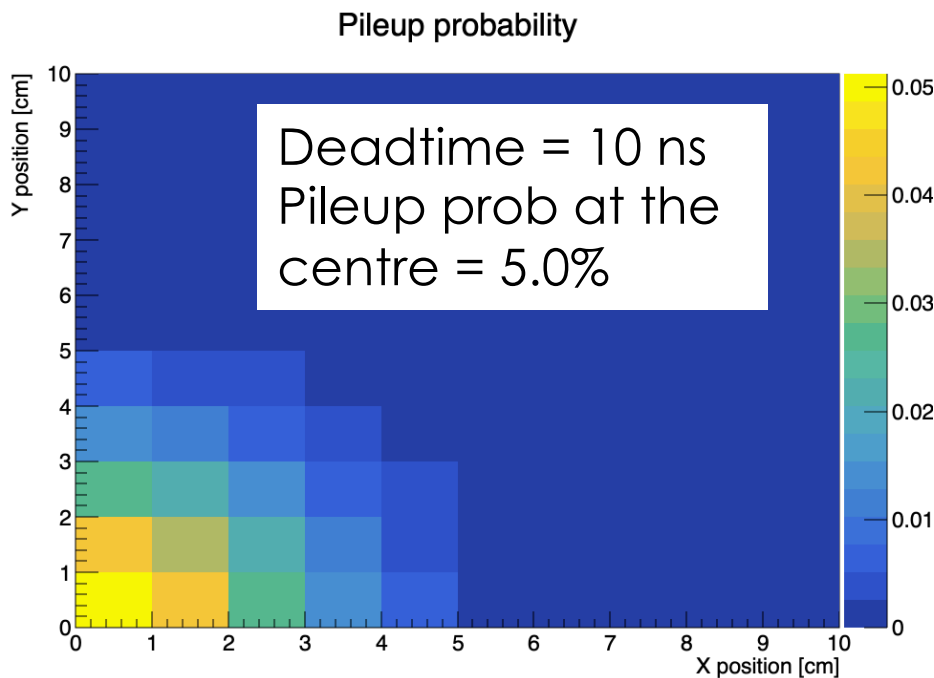
- Calculate pileup probability per readout segmented region



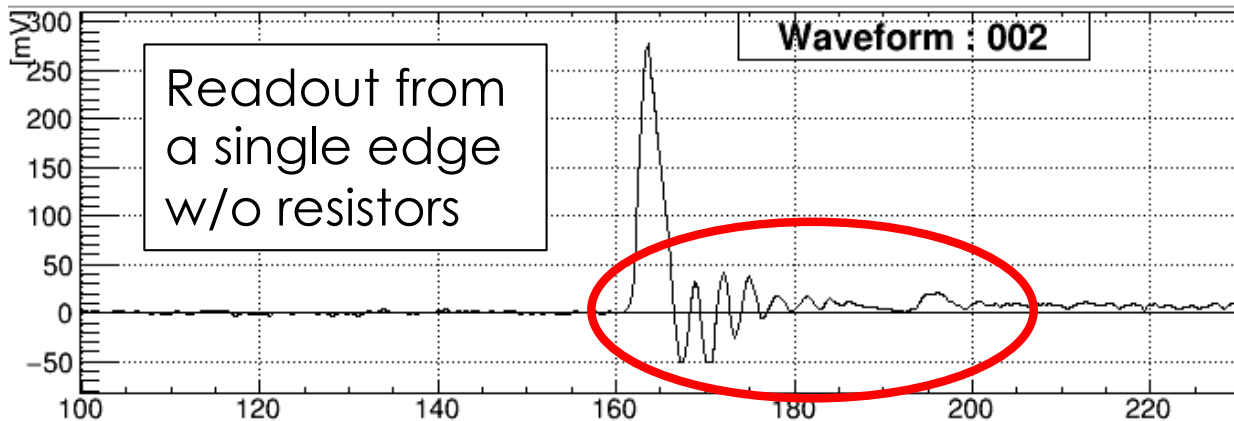
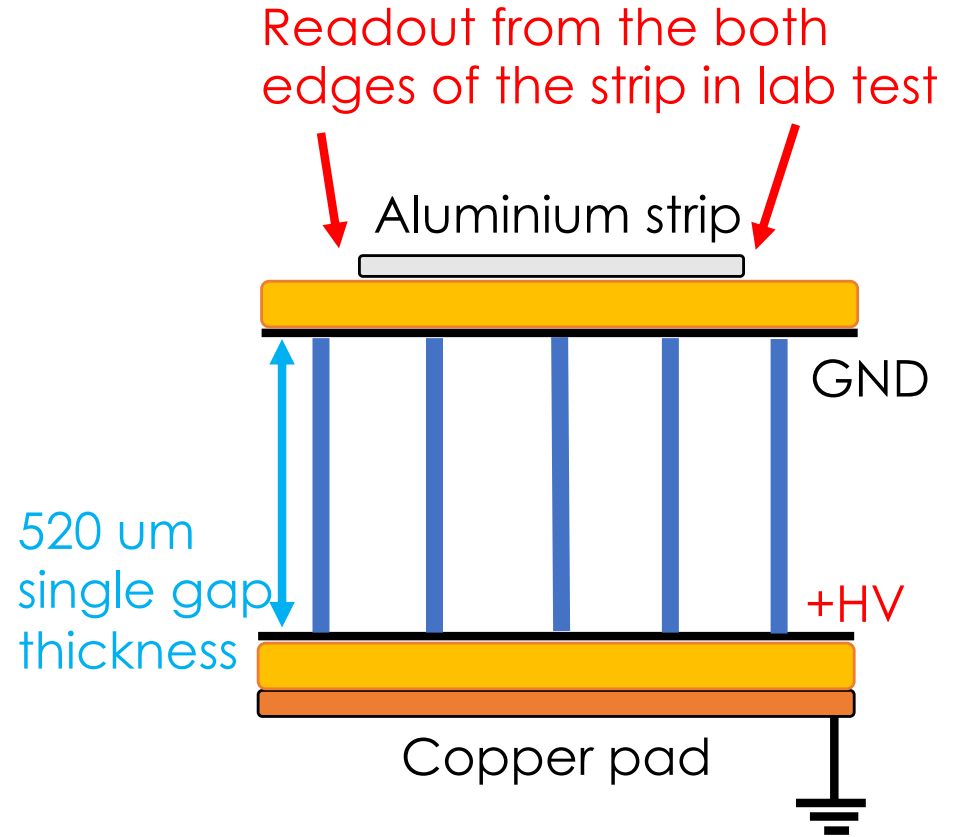
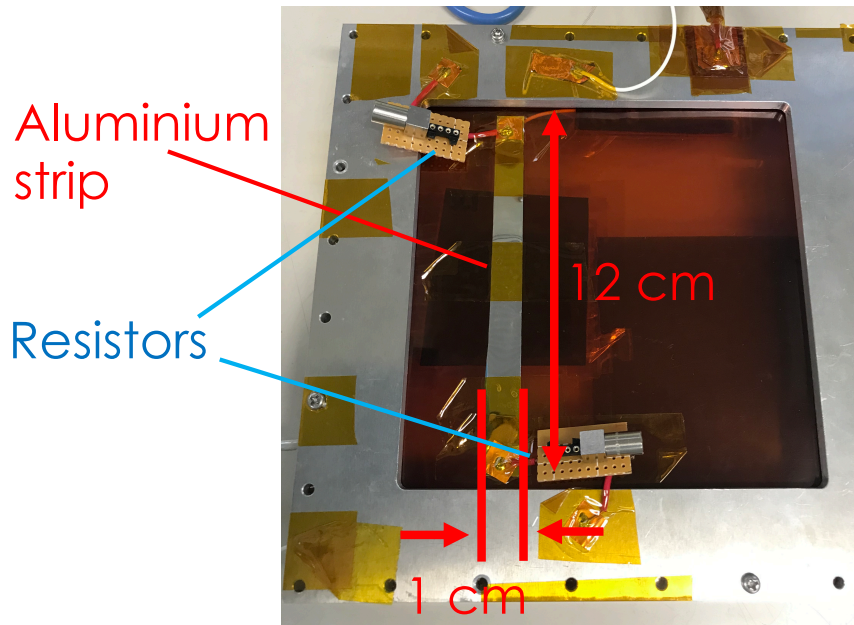
μ^+ beam divergence
 $\sigma = 2.0$ cm



RMD e^+ divergence
 $\sigma = 2.8$ cm

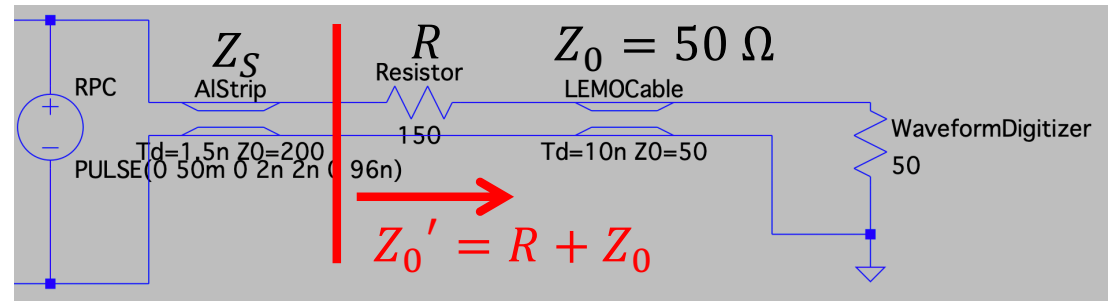


RPC readout



Reflection were observed due to impedance mismatching
→ It results in deadtime and bad effect on pileup inefficiency

Impedance



- Characteristic impedance of Al strip: Z_S
- Characteristic impedance of LEMO cable: $Z_0 = 50\ \Omega$
- Reflection coefficient $r = \frac{Z_0 - Z_S}{Z_0 + Z_S}$
- $\rightarrow Z_0 = Z_S$ for no reflection ($r = 0$)
- Insert a resistor b/w Al strip & LEMO $\rightarrow Z_0' = R + Z_0$
- Then $r = \frac{Z_0' - Z_S}{Z_0' + Z_S} \rightarrow$ Find R which gives $r = 0$ in lab test
- RPC threshold in our lab test is 10 mV

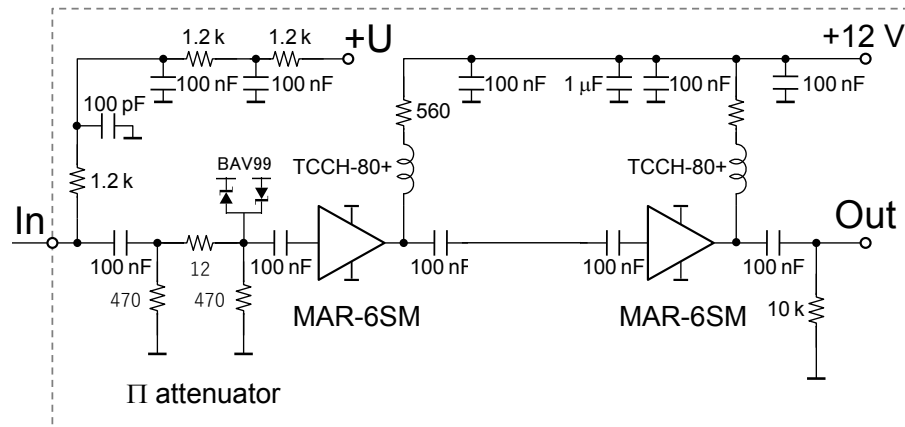
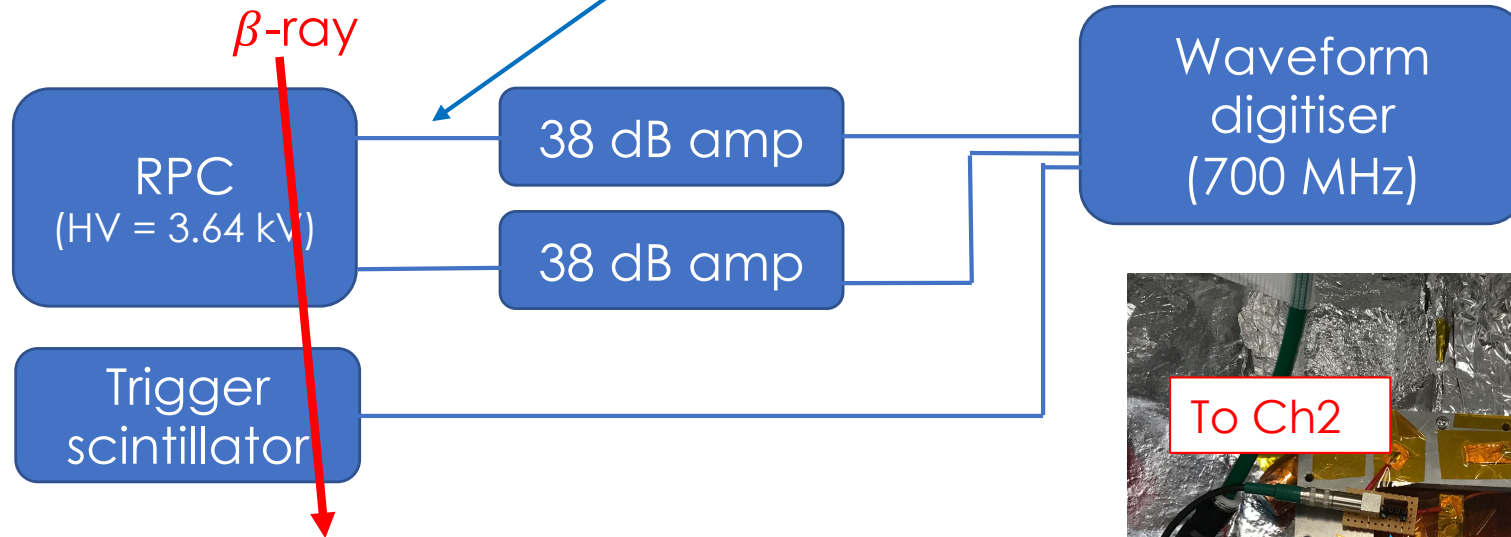
\rightarrow In lab test, find resistance which suppresses reflection to reduce deadtime

Outline

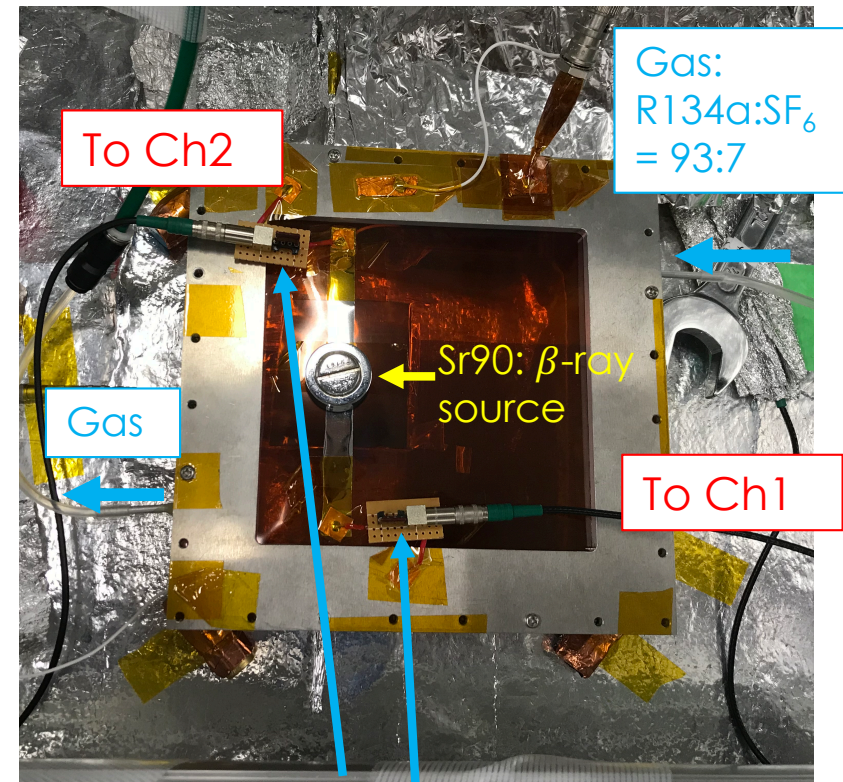
- Introduction of RPC readout
- Lab test
 - Setups
 - Waveform
 - Effect of resistors on RPC
- Summary & prospects

Setups

Resistors:
68 Ω , 82 Ω , 150 Ω



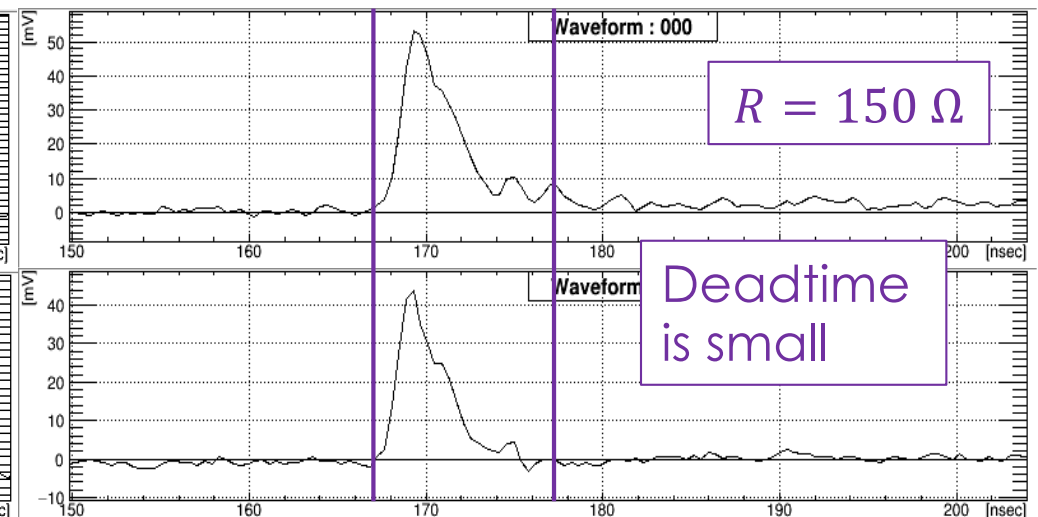
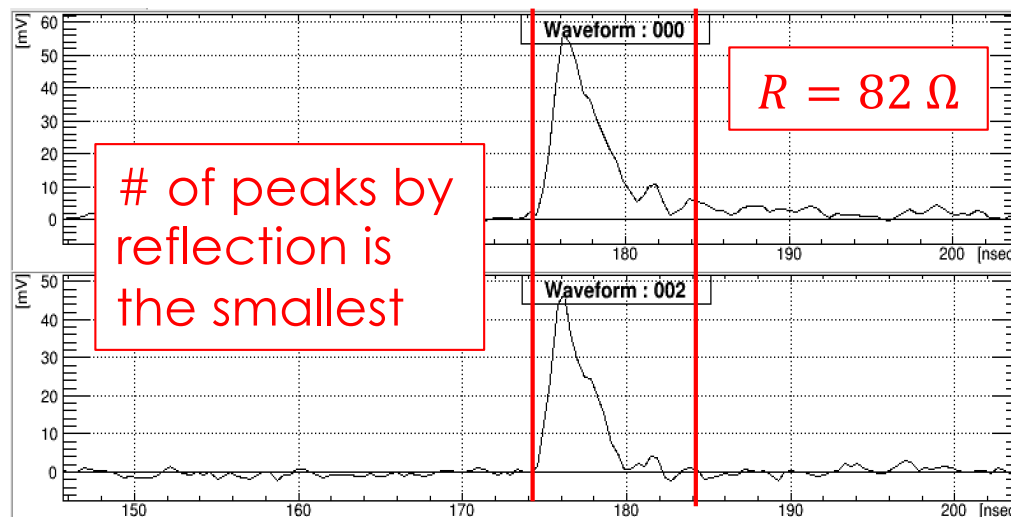
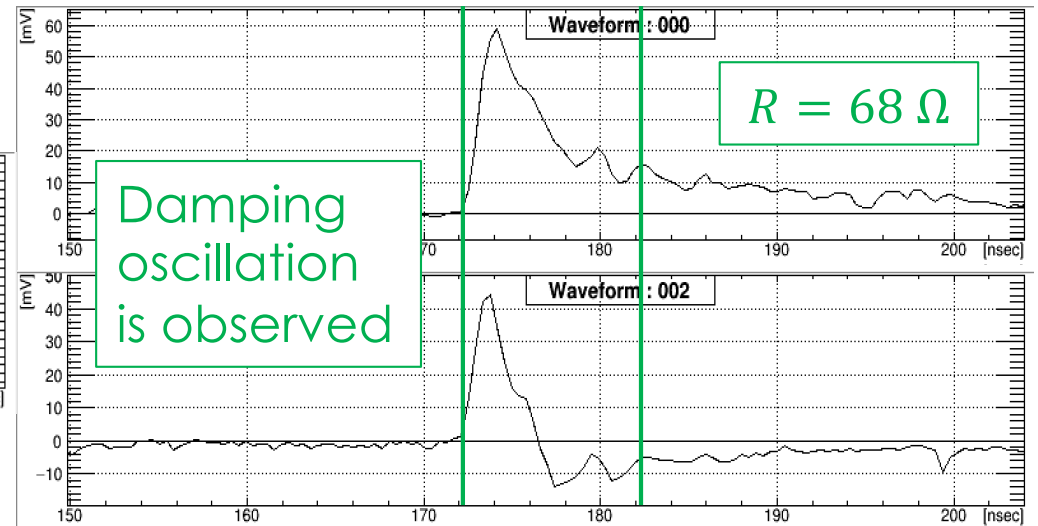
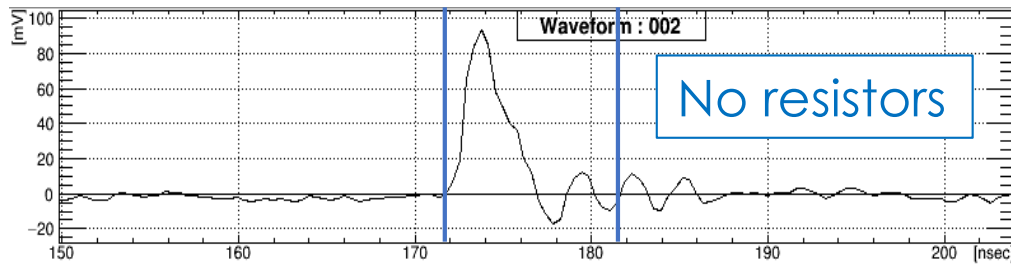
38 dB amplifier



Resistors

Waveform

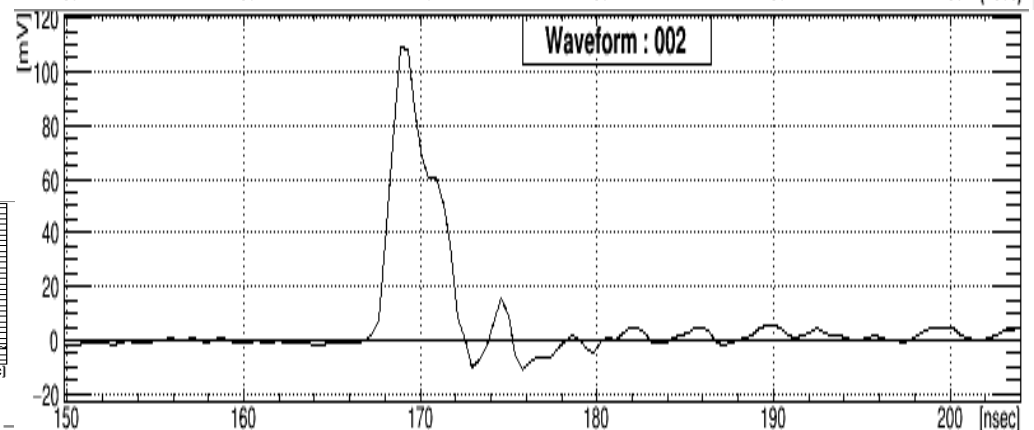
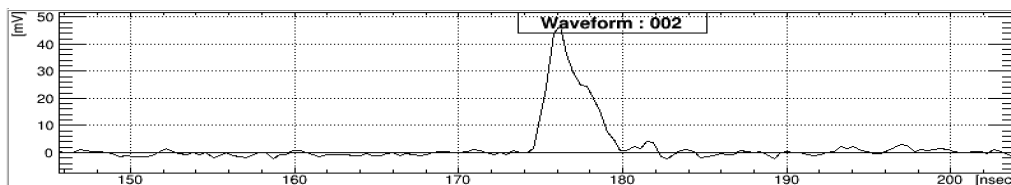
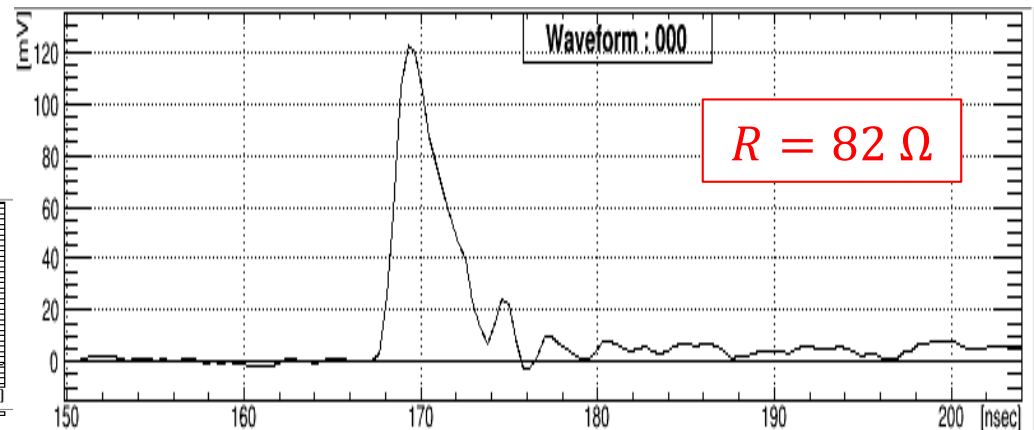
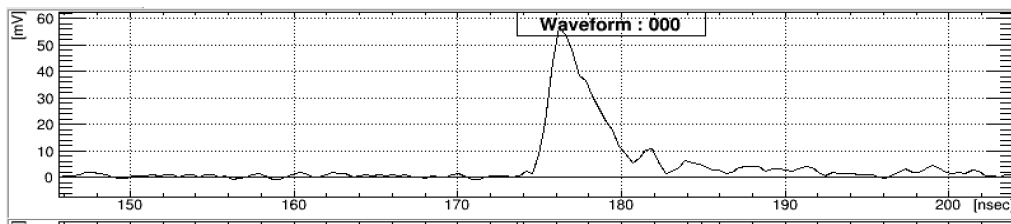
Waveform changed.
But signals still reflected.



Waveform

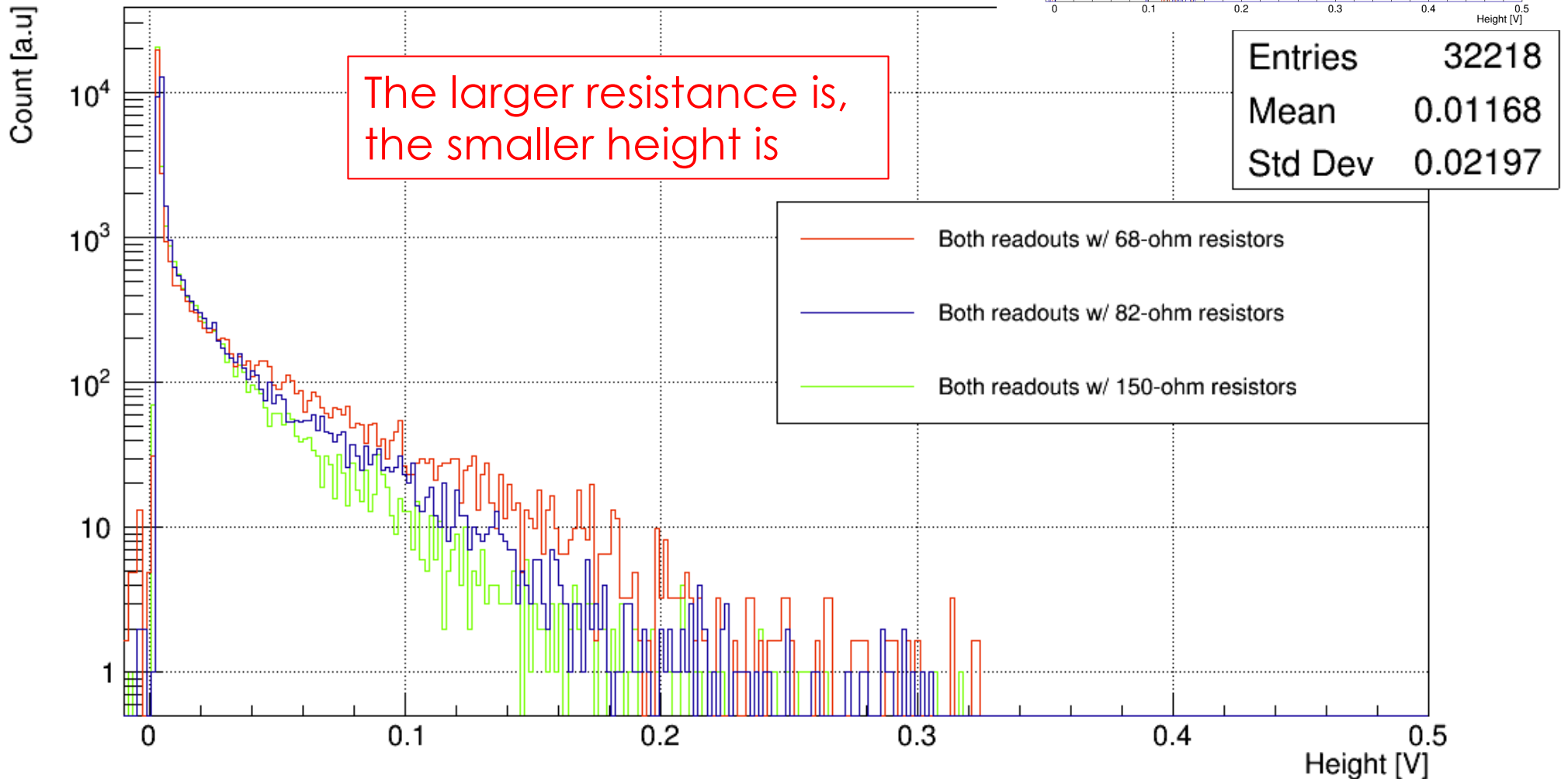
- Reflected height is dependent on signal height

- Reflection can be suppressed by inserting resistors
- Need to optimise resistance



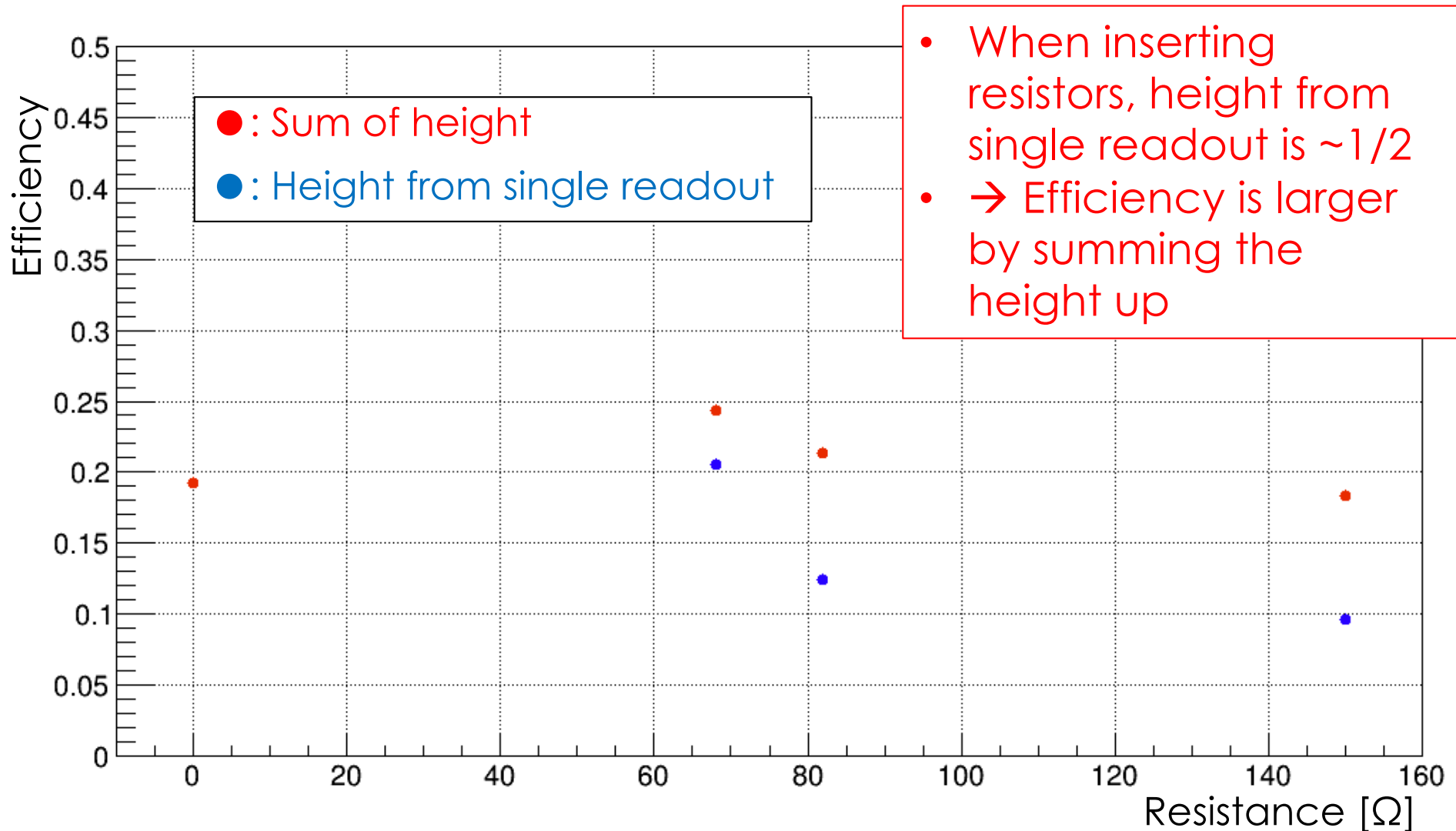
Height distribution

Height sum of both readouts



Efficiency

- When $R = 0 \Omega$, HV = 3.74 kV due to uncertainty of gap thickness
- Threshold = 10 mV



Outline

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- Lab test
 - Setups
 - Waveform
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- Summary & prospects

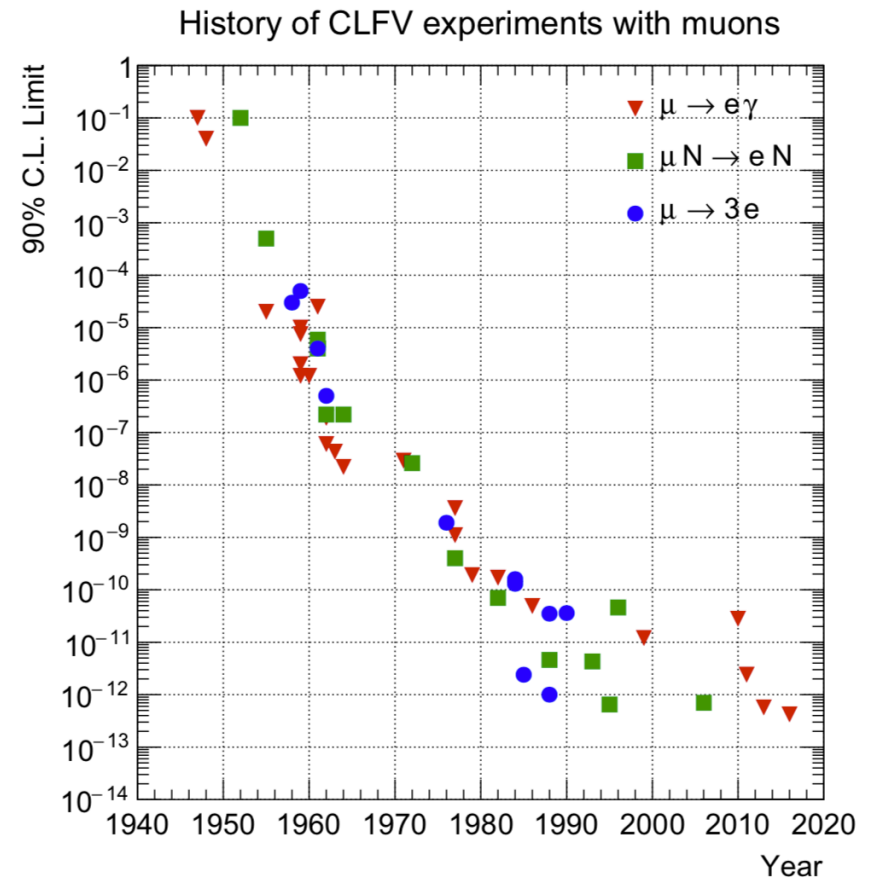
Summary & prospects

- Summary
 - Readout w/o resistors generated reflection
 - Resistors inserted b/w Al readout strip & LEMO cable can improve impedance matching
- Prospects
 - Compare w/ to w/o resistors in case of both readouts
 - Investigate reflected height quantitatively
 - Optimise readout and resistance

Backups

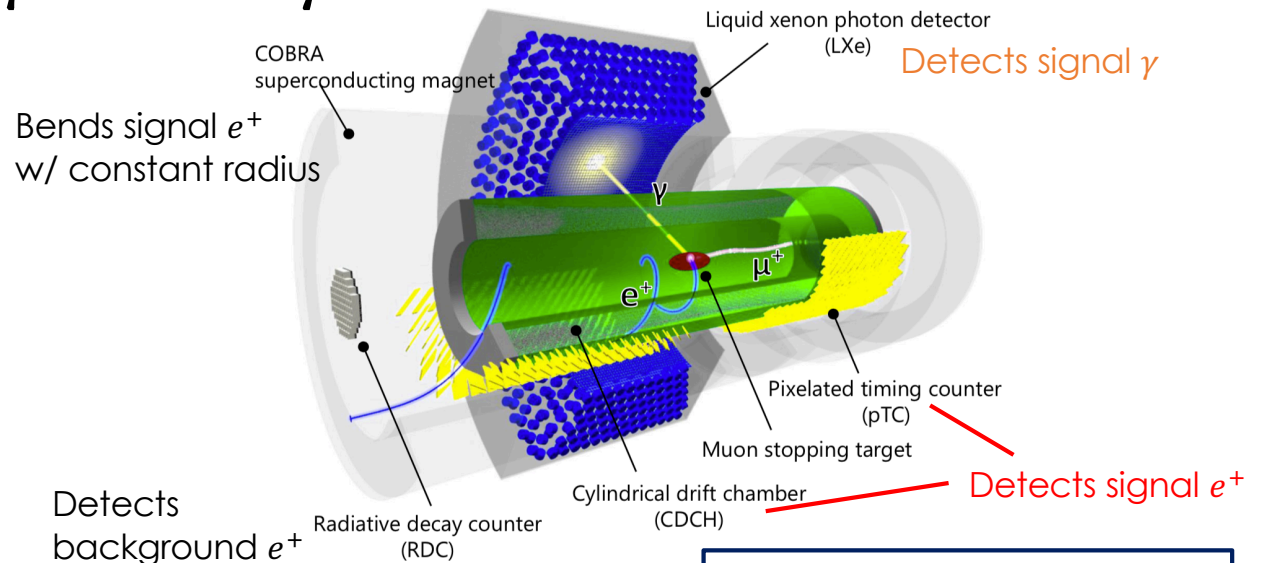
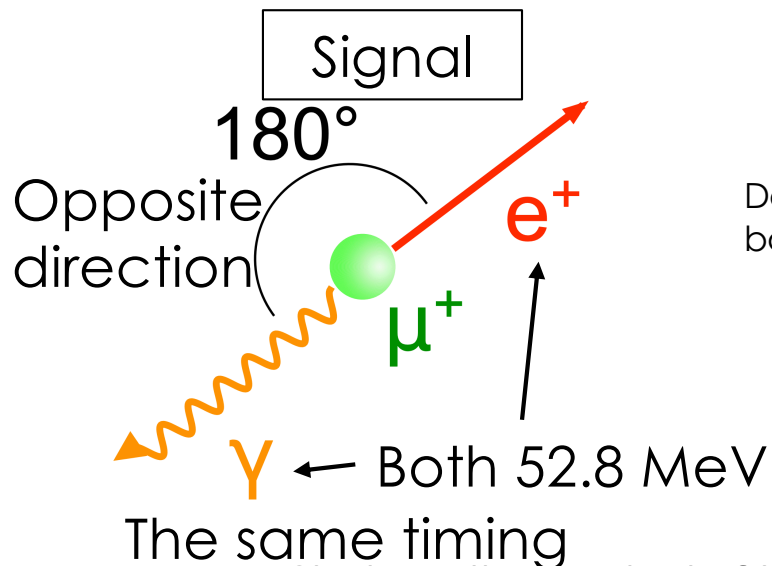
Physics of $\mu^+ \rightarrow e^+ \gamma$

- Charged lepton flavour violation (cLFV) is forbidden in the standard model (SM)
 - In the SM, $\mathcal{B}(\mu \rightarrow e \gamma) < 10^{-50}$
- Some physics models beyond the SM (SUSY-GUT, SUSY-seesaw) say $\mathcal{B}(\mu \rightarrow e \gamma)$ is $10^{-11} - 10^{-14}$
- MEG experiment gave the upper limit of $\mu \rightarrow e \gamma$ 5.3×10^{-13} for the branching ratio
- $\mu \rightarrow e \gamma$ observation strengthen makes models beyond SM



MEG II signal

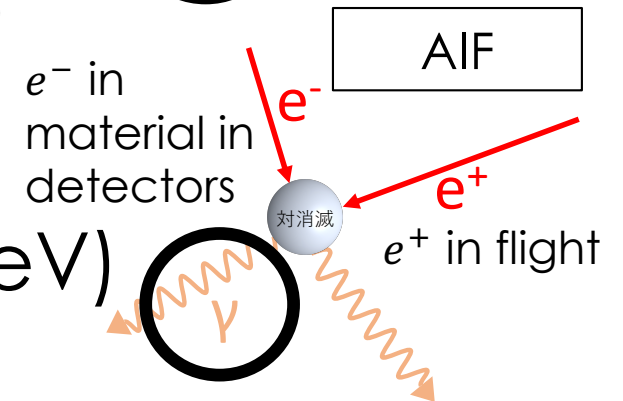
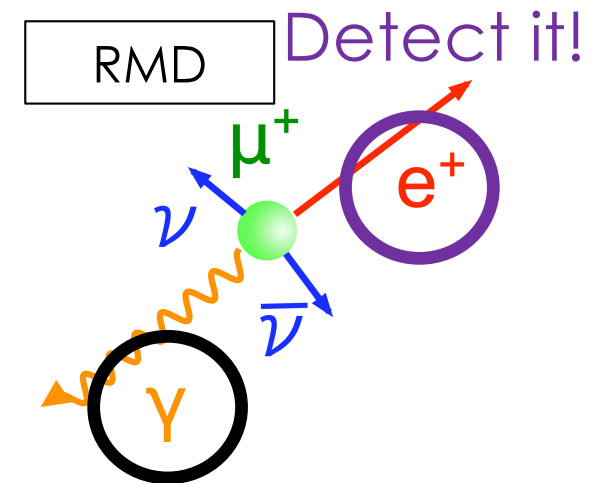
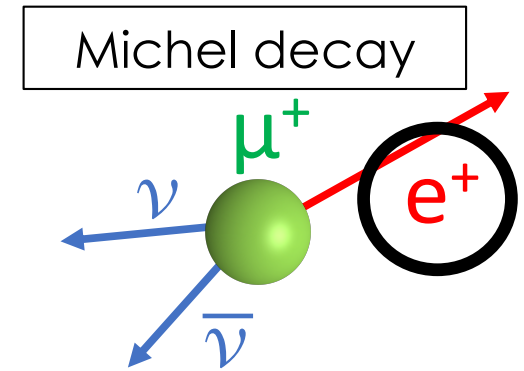
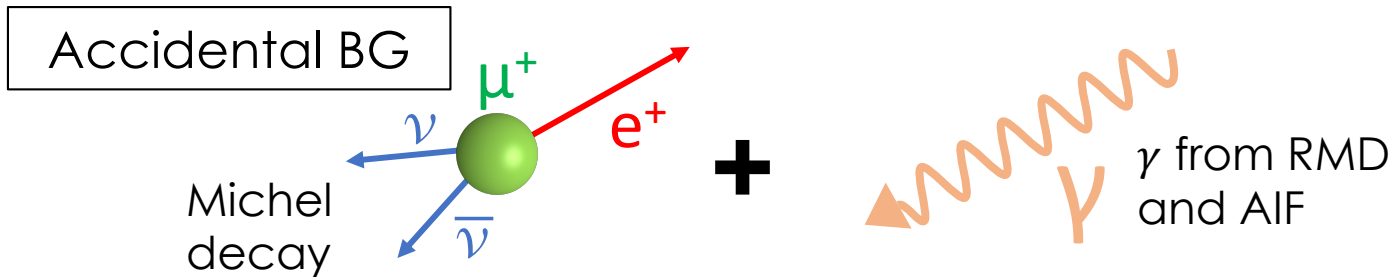
- MEG II searches for charged lepton flavour violating decay: $\mu^+ \rightarrow e^+ \gamma$
- MEG II signal is identified by the kinematics



Use the most intense μ beam:
DC and beam rate $\sim 7 \times 10^7$ /s

MEG II background

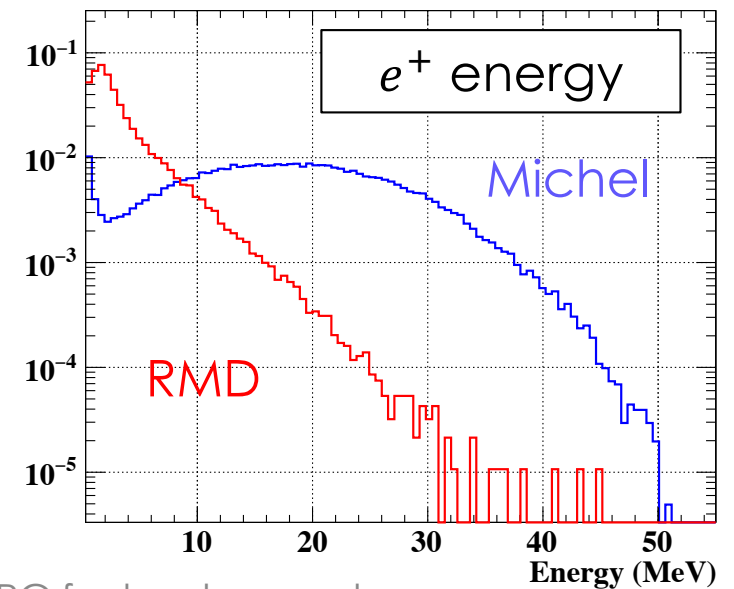
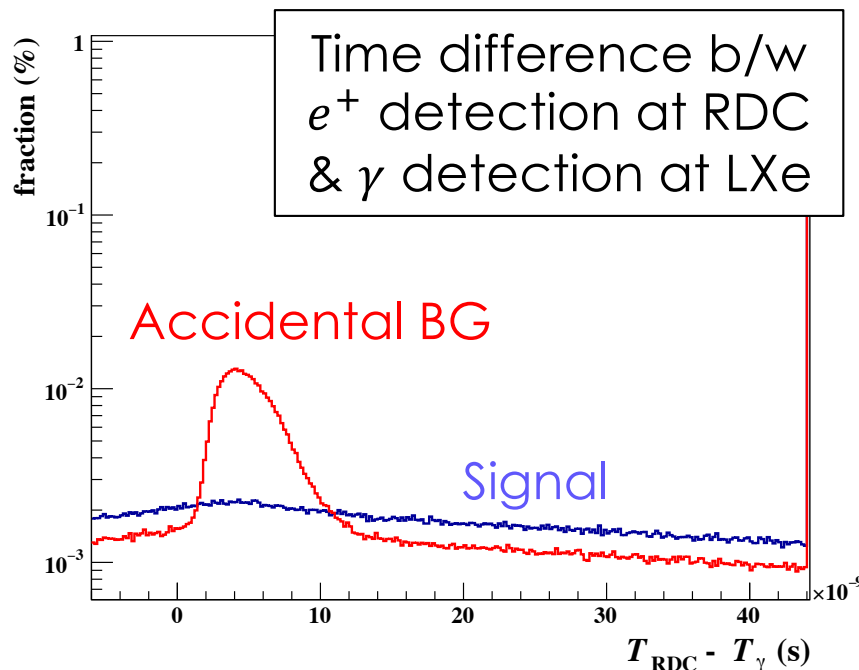
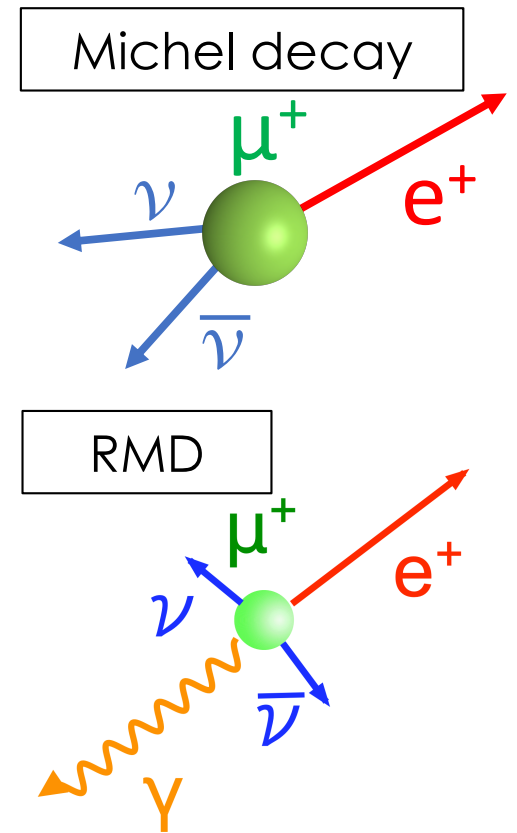
- Sources of e^+ , γ of around 52.8 MeV are these 3 reactions:
 - Michel decay
 - Radiative muon decay (RMD)
 - Annihilation in flight (AIF)



- Detect e^+ with low energy (1-5 MeV) from RMD to identify γ from RMD

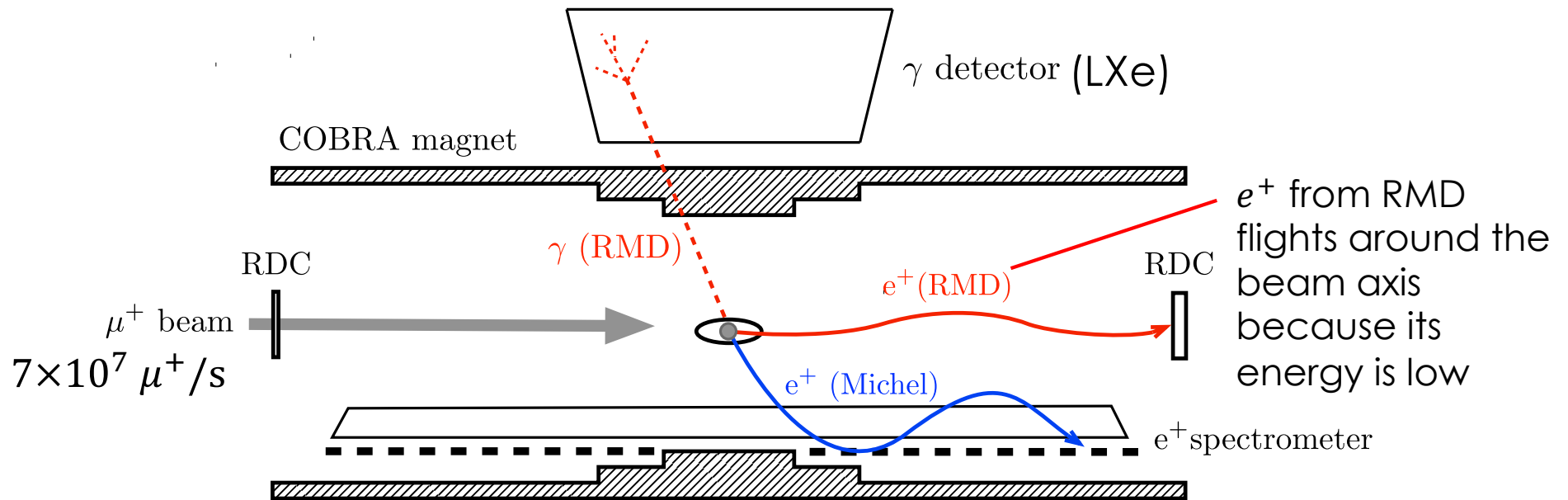
BG properties

- RMD γ is identified from
 - RMD e^+ energy
 - Time correlation b/w e^+ & γ



BG identification detectors

- Install radiative decay counters (RDCs) in both upstream and downstream



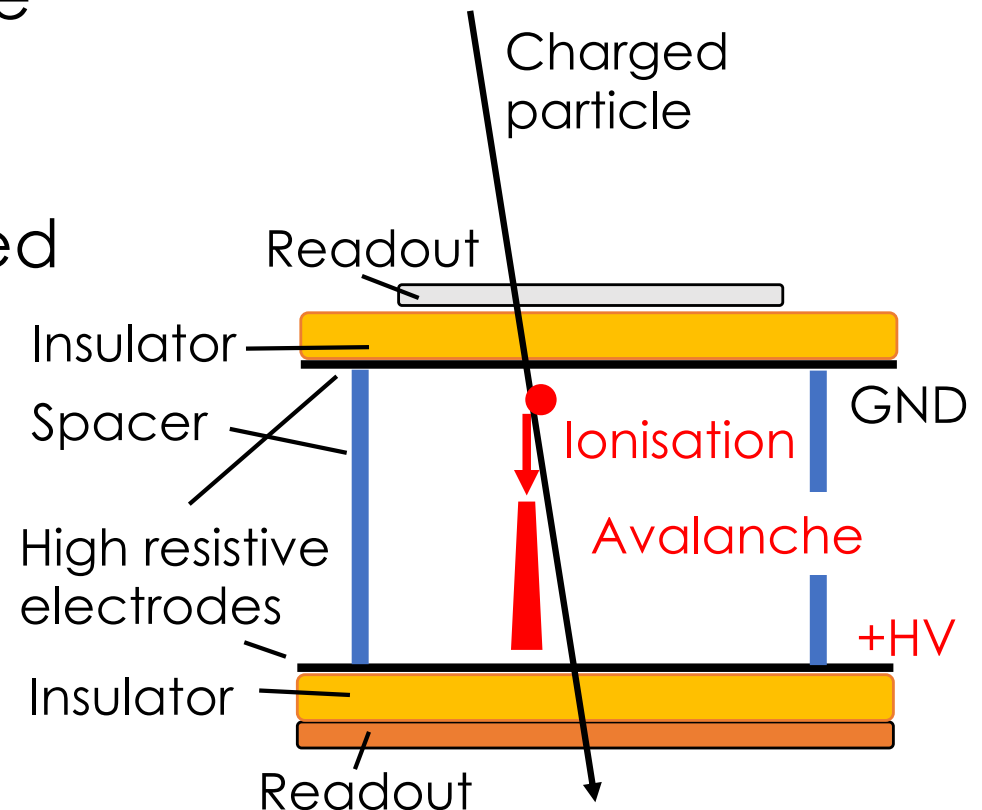
- High-intensity μ^+ beam passes through the upstream RDC
← Difficulty in developing it

Upstream RDC requirements

1. Material budget: $< 0.1\% X_0$
($\leftarrow \mu^+$ beam passes through the detector)
 2. 90% efficiency for e^+ with 1-5 MeV
 3. 1 ns time resolution
(\leftarrow RMD ID with time difference b/w e^+ & γ)
 4. Rate capability & radiation hardness
($\leftarrow 7 \times 10^7 \mu^+ /s$ with 21 MeV/c & > 60 weeks run)
 5. Detector size: 20-cm diameter
($\leftarrow 45\%$ acceptance in the one RDC, 90% in total w/ DS)
- \rightarrow Ultra-low material resistive plate chamber (RPC)

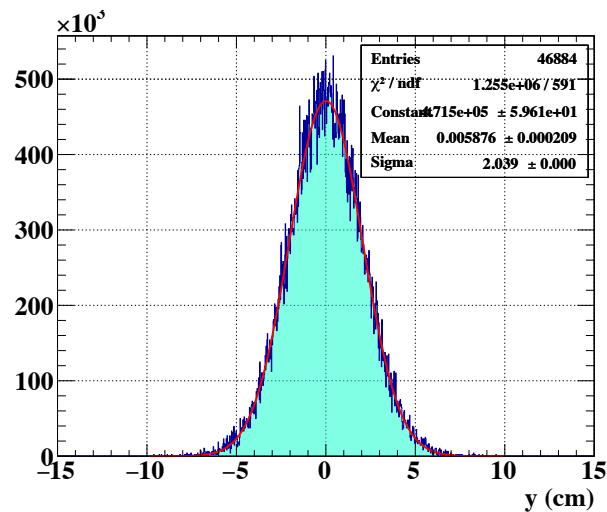
RPC: Resistive Plate Chamber

- RPC is one of gaseous detectors, uses high resistive electrodes placed face to face
- Gas is ionised when charged particles pass through RPC
- Ionised electron is accelerated by high voltage (HV)
- Avalanche occurs by accelerated electrons
- Avalanche signals are induced in readout

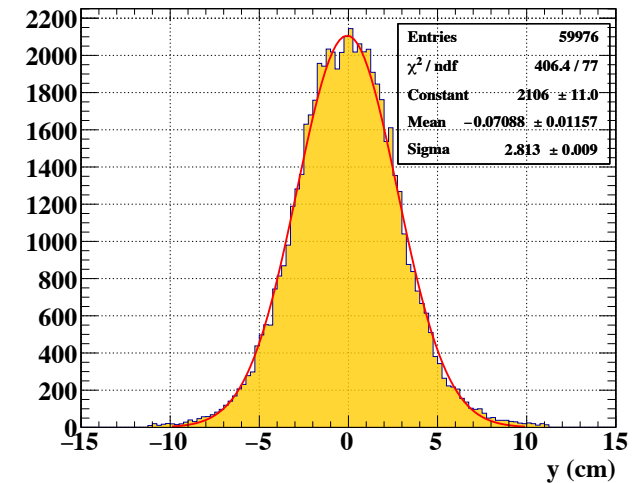


Pileup

- Calculate pileup probability per readout region in which AI strips overlap

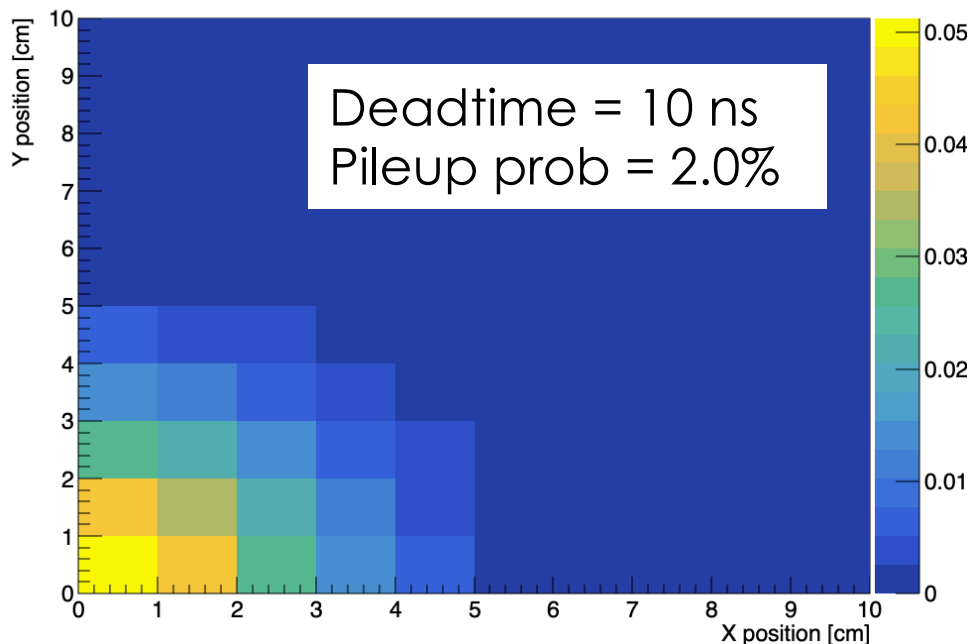


μ^+ beam divergence
 $\sigma = 2.0 \text{ cm}$

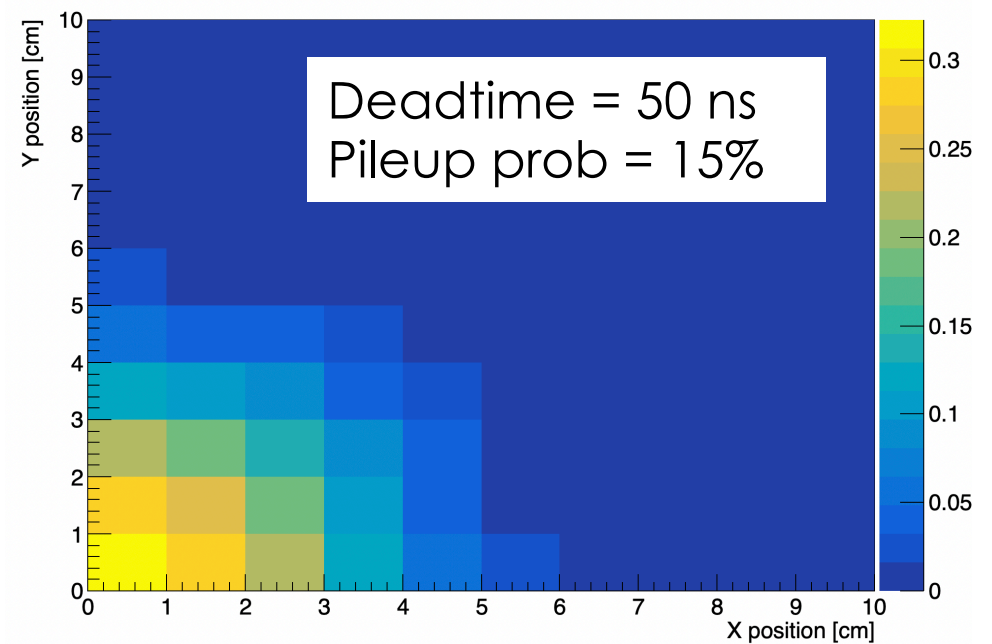


RMD e^+ divergence
 $\sigma = 2.8 \text{ cm}$

Pileup probability



Pileup probability

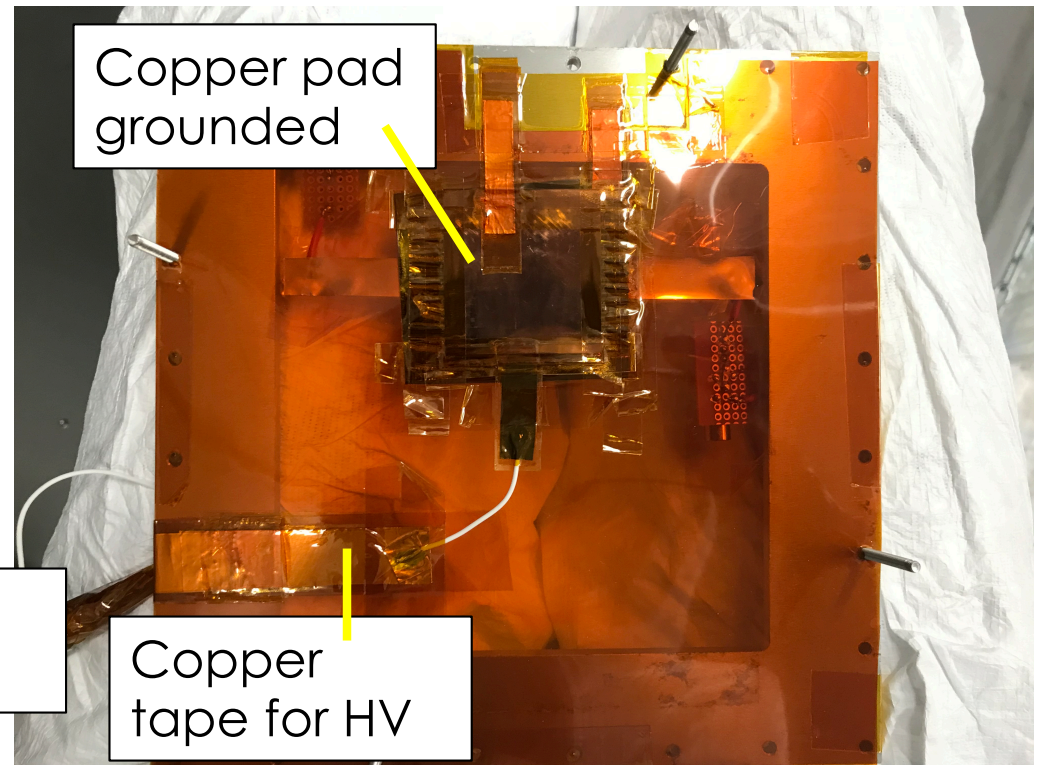
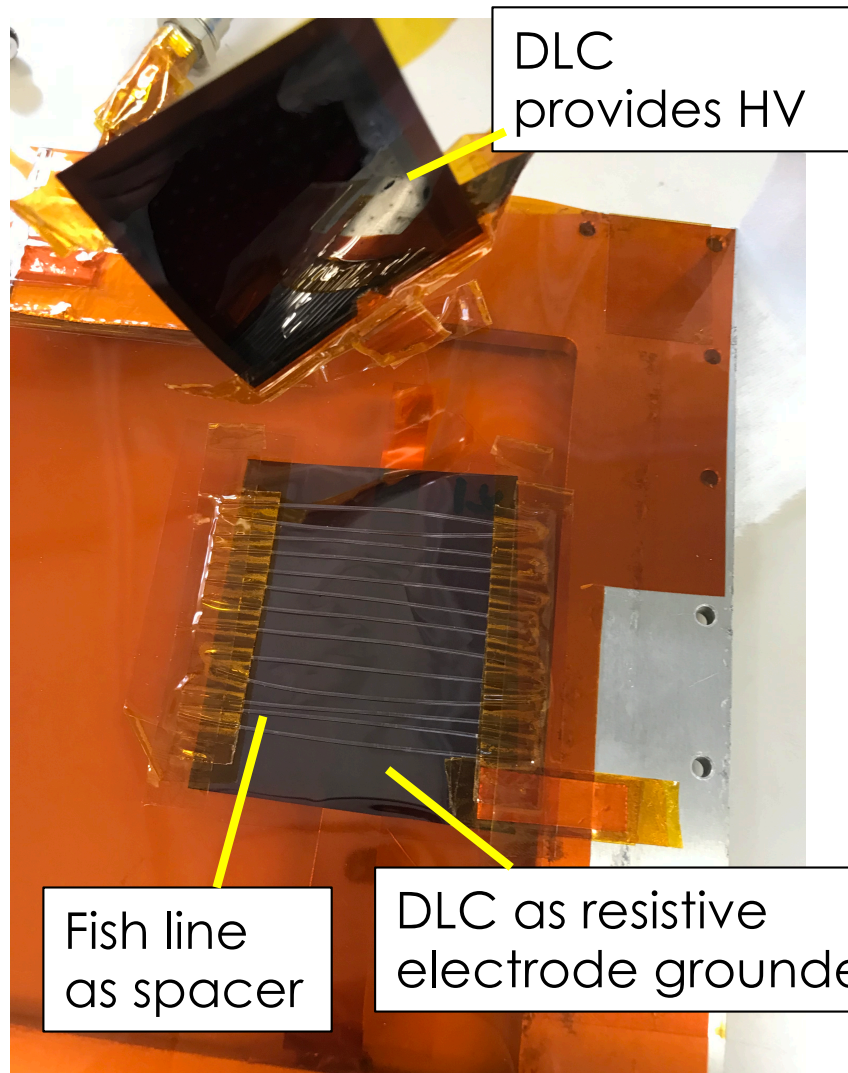


Pileup calculation

- P_i : pileup probability per readout segmented region
- ρ_i : probability to detect RMD e^+ in the segmented region (= 2.8 cm)
- Total pileup probability is given by
- $\sum_{strips=256} P_i \rho_i$
- Probability of time difference t b/w continuous μ^+ :
- $p(t) = \frac{1}{\tau} \exp\left(-\frac{t}{\tau}\right)$, where $\frac{1}{\tau}$ is μ^+ rate in region i
- Probability of pileup of μ^+ beam & RMD e^+ in region i :
- $P_i = 1 - \exp\left(-\frac{t_{dead}}{\tau}\right)$, where t_{dead} is deadtime when we cannot distinguish μ^+ & RMD e^+

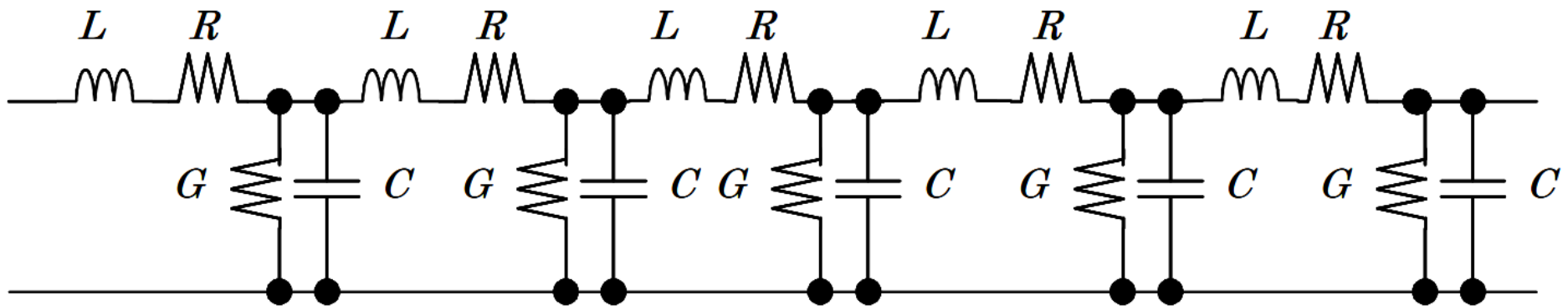
Prototype RPC

- Fish line (#10) gives 520-um gas thickness



Transmission line

- Assume Al strip is a transmission line with loss
- Conductance G is zero



R : 単位長あたりの抵抗
 L : 単位長あたりのインダクタンス
 G : 単位長あたりのアドミタンス
 C : 単位長あたりのキャパシタンス

(単位長は扱う波長に対して、充分、小さい値で考える)

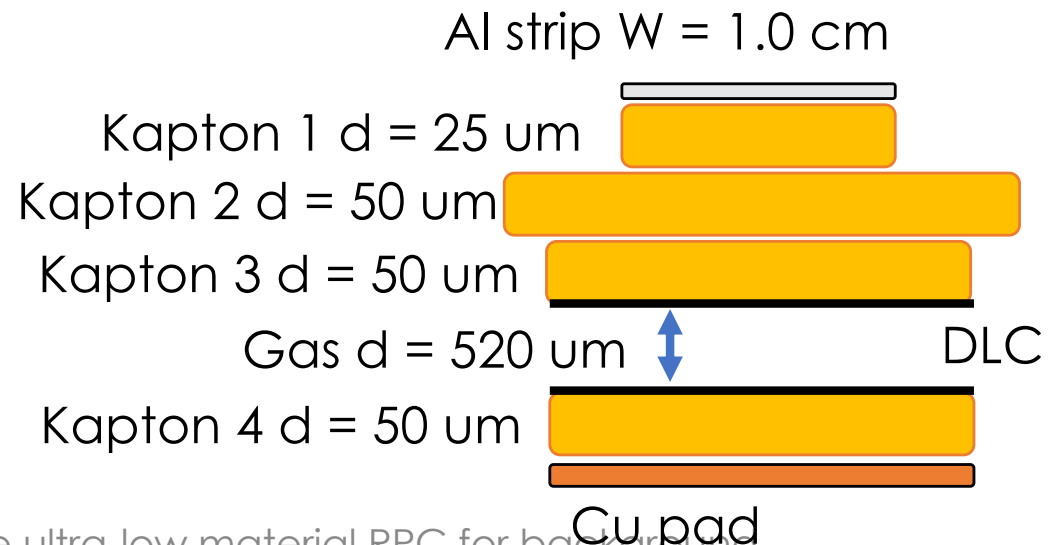
Resistance per length

- Surface resistivity $R_S = 1.1 \Omega/\text{sq}$
- $\rightarrow R = \frac{R_S}{W} = 110 \Omega/\text{m}$
- where W is width of Al strip, that is 1 cm

Property		Units	Aluminum Metallized Polyimide Film Typical Value	
			LR-PI 100AM	LR-PI 200AM
Backing Thickness		μm	25	50
Aluminum Thickness		μm	0.2-0.5	0.2-0.5
Tensile Strength		MPa	≥ 140	≥ 130
Elongation		%	≥ 45	≥ 45
Shrinkage, at 150°C		%	0.20	0.20
Surface Resistivity	The side of PI Film	Ω	$\geq 1 \times 10^{12}$	$\geq 1 \times 10^{12}$
	The side of Aluminum	Ω	$< 10^3$	$< 10^3$

Capacitance per length

- Think of geometry like this figure
- Ignore DLC plate because DLCs are sputtered on kaptons
- Kapton's relative permittivity $\epsilon_r = 3.3$



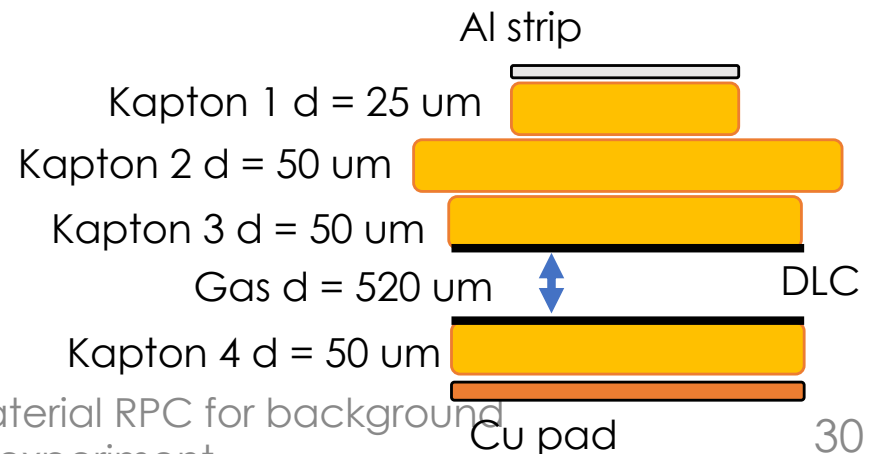
Capacitance per length

- Give strip charge per length q
- From Gauss's law, electric field is
- $q = \epsilon_0 \epsilon_r E W \rightarrow E = \frac{q}{\epsilon_0 \epsilon_r W}$
- From the field, potential diff b/w Al strip and Cu pad is

$$V = \int_0^d \frac{q}{\epsilon_0 \epsilon_r W} dx = \frac{q d}{\epsilon_0 \epsilon_r W}$$

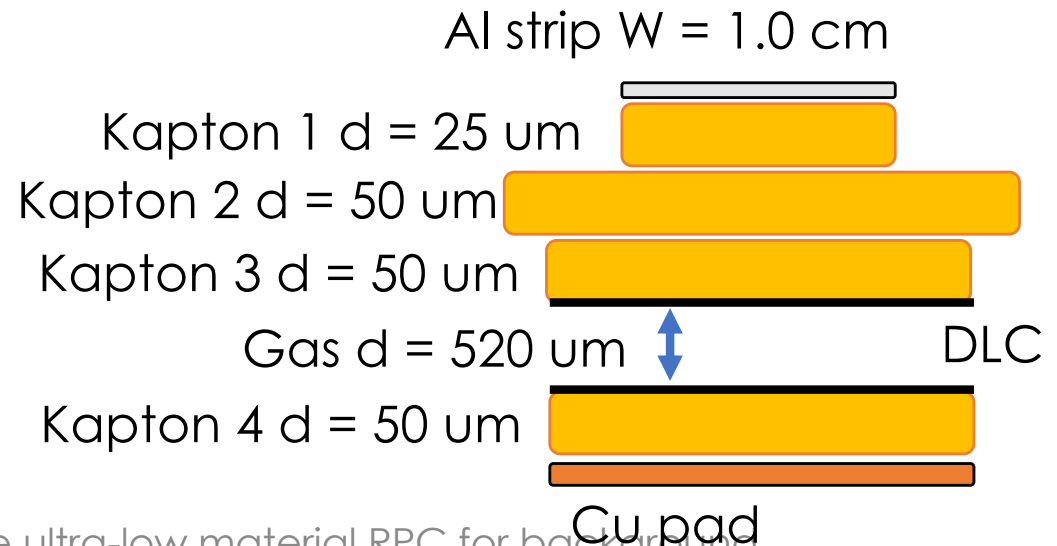
$$\text{From } V = \frac{q}{C'}$$

$$C_i = \frac{\epsilon_0 \epsilon_r W}{d}$$



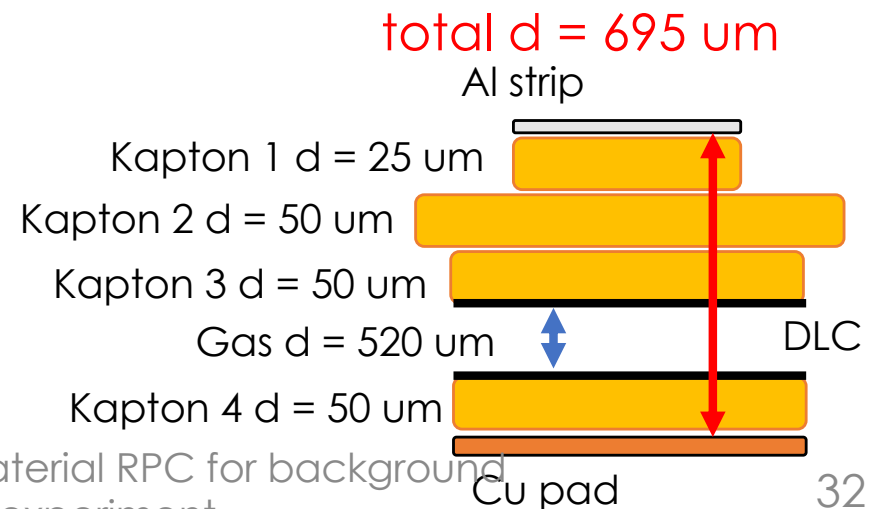
Capacitance per length

- From $C_i = \frac{\epsilon_0 \epsilon_r W}{d}$, where C_i is capacitance per length in layer i
- Total capacitance $C = 155 \text{ pF/m}$



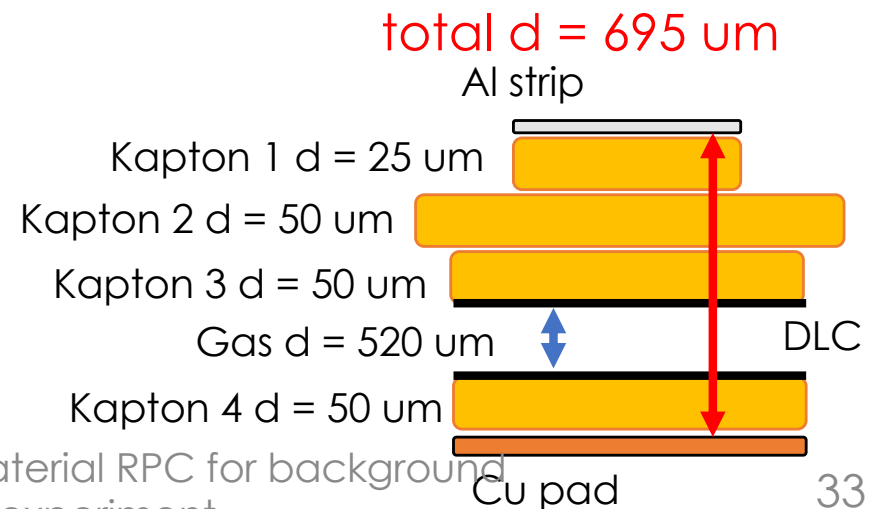
Inductance per length

- Think of geometry like this figure
- Assume current J flows only in Al strip (No current in Cu pad)
- From Ampere's law, magnetic field is
- $2W\mu B = J \rightarrow B = \frac{\mu J}{2W}$
- Permeability $\mu = \mu_0$



Inductance per length

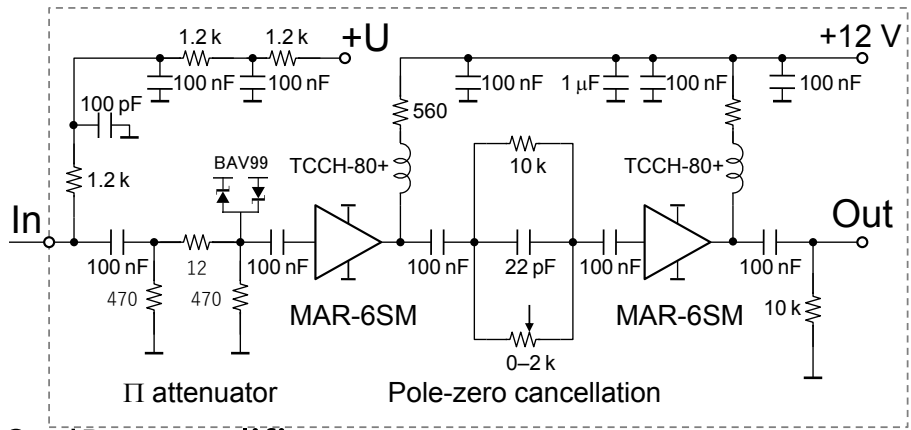
- Magnetic flux Φ is
- $\Phi = \int \frac{\mu_0 J}{2W} dS = \frac{\mu_0 J}{2W} d$
- From Φ , calculate V, L
- $V = -\frac{d\Phi}{dt} = -\frac{\mu_0 d}{2W} \frac{dJ}{dt} = -L \frac{dJ}{dt} \rightarrow L = \frac{\mu_0 d}{2W} \text{ H/m}$
- $L = 44 \text{ nH/m}$



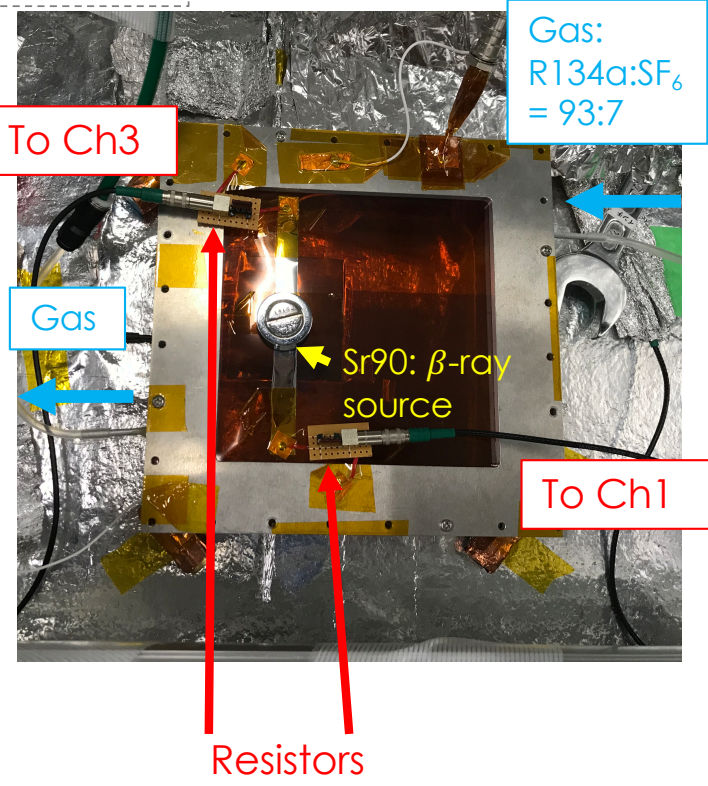
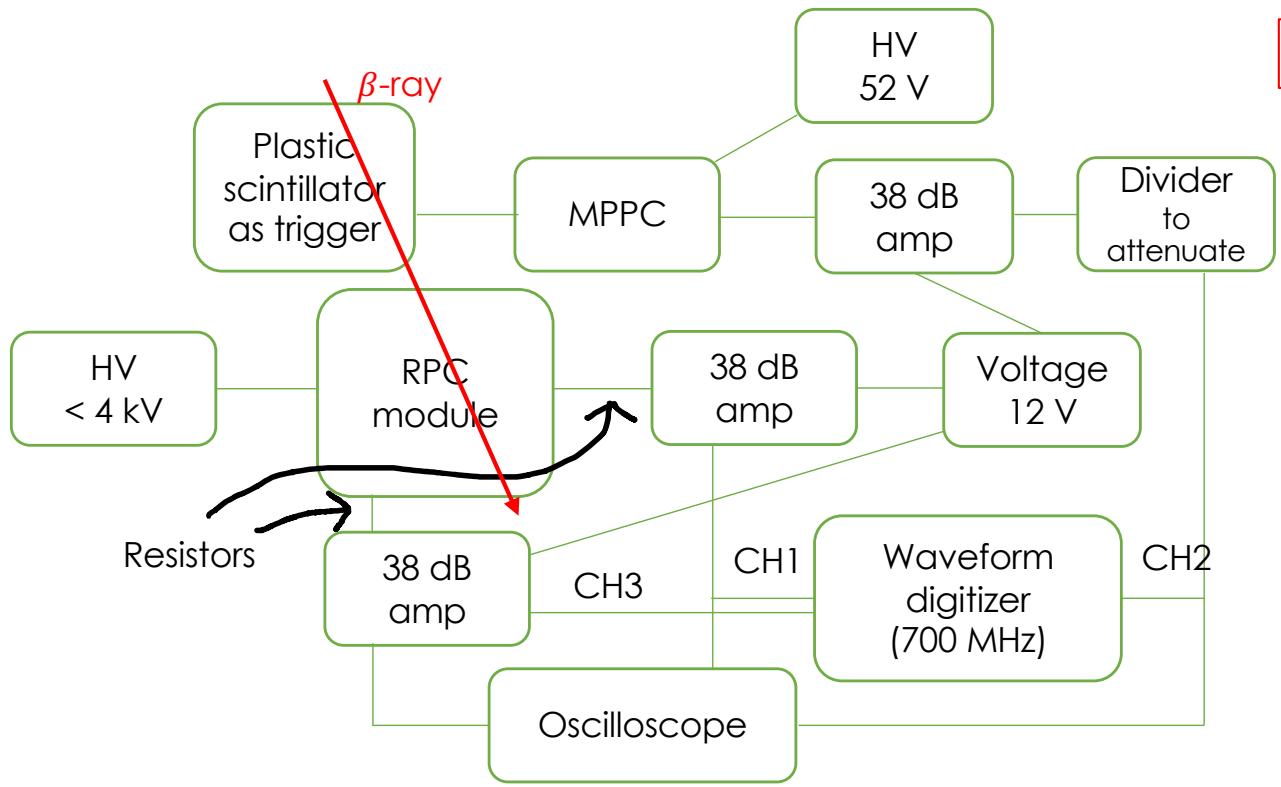
Characteristic impedance

- Need to consider resistance R because we cannot ignore loss
- Characteristic impedance is
- $|Z_0| = \sqrt{\frac{R^2 + (\omega L)^2}{(\omega C)^2}}$
- where ω is angular frequency
- Assume signals are triangle waves whose width is 5 ns
- In this case, assume $\omega = 628 \text{ rad}/\mu\text{s}$
- $\rightarrow |Z_0| = \sqrt{\frac{R^2 + (\omega L)^2}{(\omega C)^2}} = 17 \Omega$
- But I estimate $Z_0 > 50 \Omega$ from observation of reflection

Setups

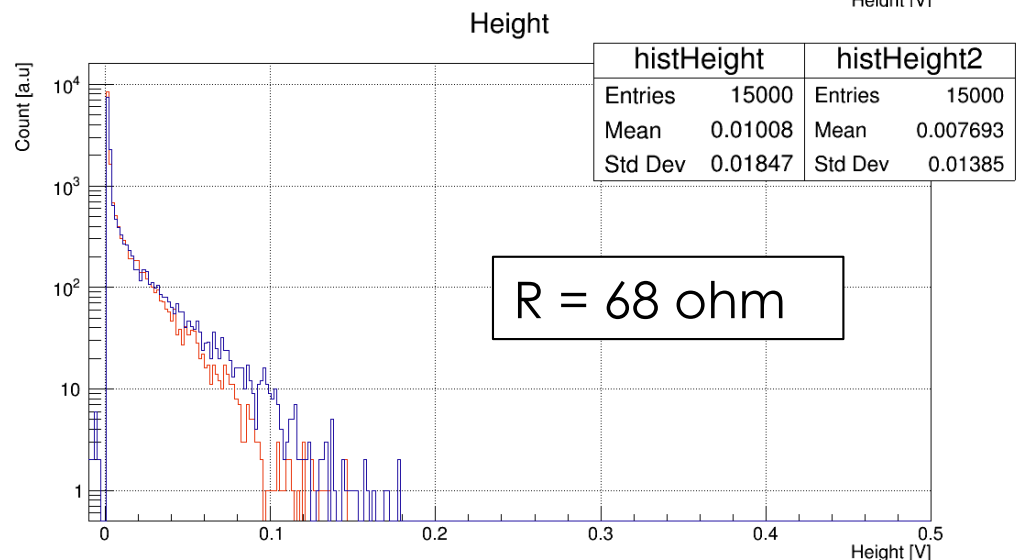
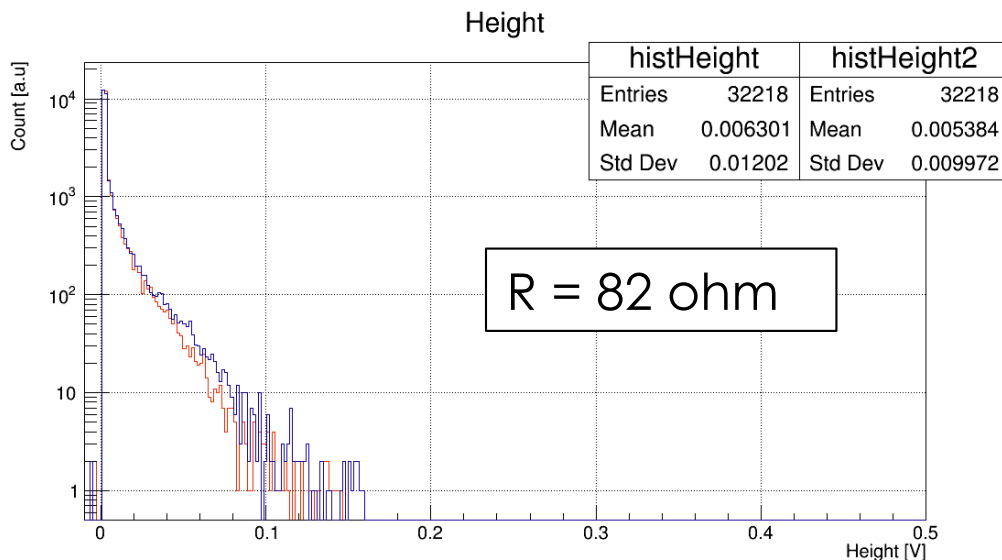
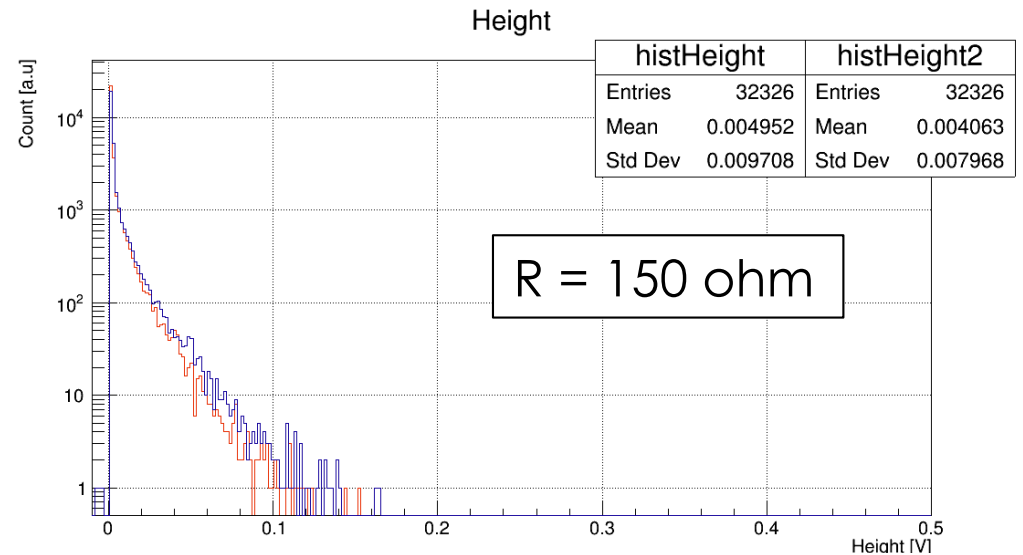


38 dB amplifier



RPC performance w/ resistors

- Each histogram expresses voltage height induced in each side
- Height is dependent on resistance because voltage drop occurs at resistors



RPC performance w/ resistors

- These histograms express the sum of voltage at both sides of Al strip
- Height sum is dependent on resistance because voltage drop occurs at resistors as well as height from each side

